# MSKSEMI 美森科













**ESD** 

TV

TSS

MOV

GDT

PLED

**BSS84AK-MS** 

**Product specification** 





## **General Features**

- -55 V,-0.3A, RDS(ON) =4.0Ω@VGS = 10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- ESD protected up to 2KV

# **Application**

- Notebook
- \_ Load Switch
- Battery Protection

# **Reference News**

PACKAGE OUTLINE	Pin Configuration	Marking
SOT-23	Go	WVS*



# Absolute Maximum Ratings (TA=25℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	-55	V
Vgs	Gate-Source Voltage	±20	V
l <sub>D</sub>	Drain Current – Continuous (T <sub>A</sub> =25°C)	-0.3	Α
	Drain Current – Continuous (T <sub>A</sub> =70°C)	-0.2	А
Ірм	Drain Current – Pulsed <sup>1</sup>	-1.2	Α
Po	Power Dissipation (T <sub>A</sub> =25°C)	1.0	W
ILD	Power Dissipation – Derate above 25°C	12.5	mW/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
RθJA	Thermal Resistance Junction to ambient		80	°C/W

# Electrical Characteristics (TJ=25 $^{\circ}$ C , unless otherwise noted)

#### Off Characteristics

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>G</sub> s=0V , I <sub>D</sub> =-250uA	-55			V
Ipss	Drain-Source Leakage Current	V <sub>DS</sub> =-55V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			- 1	uA
IDSS	Diam-Source Leakage Current	V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			- 10	uA
lgss	Gate-Source Leakage Current	V <sub>GS=</sub> ±20V , V <sub>DS</sub> =0V			±20	uA

#### On Characteristics

R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		V <sub>GS</sub> =-10V , I <sub>D</sub> =-0.3A		4.0	5	Ω
		Vgs=-4.5V , ID=-0.2A		3.5	6.0	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-1.0	- 1.7	-2.5	V
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-0.3A		0.4		S



# Dynamic and switching Characteristics

Qg	Total Gate Charge <sup>2, 3</sup>			2.8	
Qgs	Gate-Source Charge <sup>2,3</sup>	VDS=-30V , VGS=-10V , ID=-0.3A		0.96	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2,3</sup>			0.6	
Td(on)	Turn-On Delay Time <sup>2, 3</sup>			3	
Tr	Rise Time <sup>2,3</sup>	<sup>3</sup> V <sub>DD</sub> =-30V , V <sub>GS</sub> =-10V , R <sub>G</sub> =6Ω		5	
Td(off)	Turn-Off Delay Time <sup>2,3</sup>	ID=-0.3A		14	 ns
Tf	Fall Time <sup>2,3</sup>			9	
Ciss	Input Capacitance			30.5	
Coss	Output Capacitance	V <sub>DS</sub> =-30V , V <sub>GS</sub> =0V , F=1MHz		15.1	 pF
Crss	Reverse Transfer Capacitance			7	

# **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-0.3	Α
Isм	Pulsed Source Current	VG-VD-0V , Force Current			-0.6	Α
VsD	Diode Forward Voltage	Vgs=0V , Is=-0.2A , TJ=25°C			-1.2	V
Trr	Reverse Recovery Time	VR=-50V, IS=-0.3A		13.5		nS
Qrr	Reverse Recovery Charge	di/dt=100A/ps, TJ=25C		3		nC

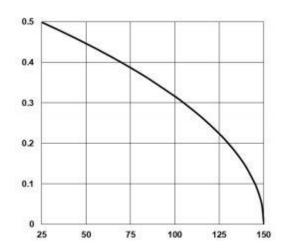
#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. Essentially independent of operating temperature.



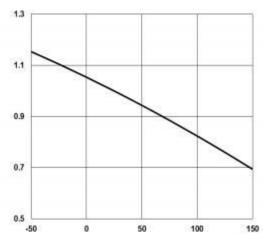
-ID , Continuous Drain Current (A)

Normalized Gate Threshold Voltage



 $T_J$  , Junction Temperature (°C)

Fig.1 Continuous Drain Current vs. Tc



T<sub>J</sub> , Junction Temperature (°C)

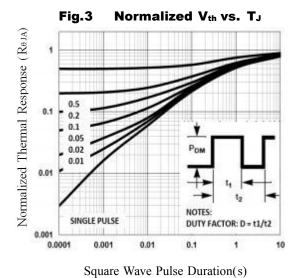
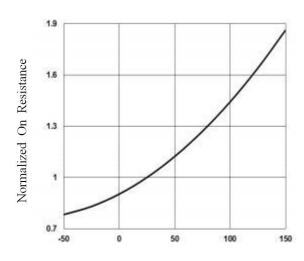


Fig. 5 Normalized Transient Impedance



T<sub>J</sub> , Junction Temperature (°C)

Fig. 2 Normalized RDSON vs. TJ

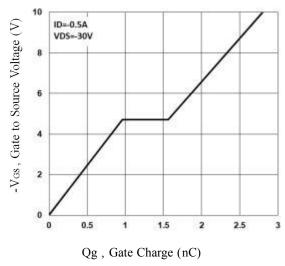
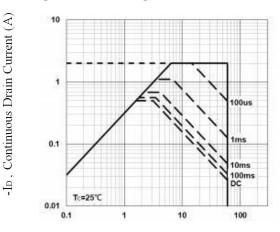


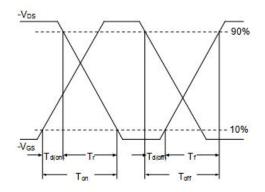
Fig.4 Gate Charge Waveform



-VDS,Drain to Source Voltage (V)

Fig.6 Maximum Safe Operation Area





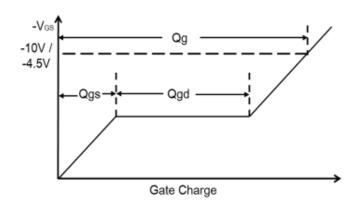


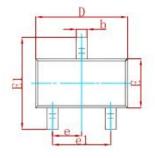
Fig. 7 Switching Time Waveform

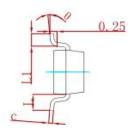
Fig. 8 Gate Charge Waveform

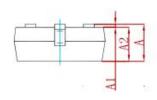




## PACKAGE MECHANICAL DATA

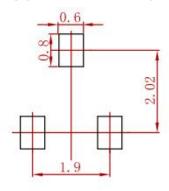






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037 TYP	
e1	1.800	2.000	0.071	0.079
L	0.550	REF	0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

# **Suggested Pad Layout**



### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
BSS84AK-MS	SOT-23	3000



# **Attention**

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all MSKSEMI Semiconductor products described or contained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer'sproducts or equipment.
- MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possiblethat these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents—or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuitsfor safedesign, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.

# 单击下面可查看定价,库存,交付和生命周期等信息

>>MSKSEMI (美森科)